

Materials List for

# Nanoscale Characterization of Liquid-Solid Interfaces by Coupling Cryo-Focused Ion Beam Milling with Scanning Electron Microscopy and Spectroscopy

Taylor Moon<sup>1</sup>, Michael Colletta<sup>1</sup>, Lena F. Kourkoutis<sup>1,2</sup>

<sup>1</sup>School of Applied and Engineering Physics, Cornell University <sup>2</sup>Kavli Institute at Cornell for Nanoscale Science

## Corresponding Author

Lena F. Kourkoutis

lena.f.kourkoutis@cornell.edu

## Citation

Moon, T., Colletta, M., Kourkoutis, L.F. Nanoscale Characterization of Liquid-Solid Interfaces by Coupling Cryo-Focused Ion Beam Milling with Scanning Electron Microscopy and Spectroscopy. *J. Vis. Exp.* (185), e61955, doi:10.3791/61955 (2022).

## Date Published

July 14, 2022

## DOI

10.3791/61955

## URL

jove.com/video/61955

## Materials

Name	Company	Catalog Number	Comments
INCA EDS	Oxford instruments		Control software for X-max 80
PP3010T Cryo-preparation system	Quorum Technologies, Inc.		FIB/SEM cryogenic preparation system. Includes pumping station, transfer rod system, preparation (prep) chamber, cryogenic stages, sample shuttles
Strata 400 DualBeam System	FEI Co. (now Thermo Fisher Scientific)		Dual beam FIB/SEM
X-Max 80	Oxford Instruments		80mm2 EDX detector
xT Microscope Control	FEI Co. (now Thermo Fisher Scientific)		Software for controlling FEI Strata